Alexandria, Virginia 22313-1450

In Re Patent Application of:		
Steven N. Towle	Examiner: McDonald, Rodney Glenn	
Application No.: 10/082,997	Art Unit: 1753	
Filed: February 25, 2002	RECEIVED	
For: METHOD FOR IMPROVING THERMAL) STABILITY OF FLUORINATED AMORPHOUS	DEC 15 2003	
CARBON LOW DIELECTRIC (CONSTANT MATERIALS)	TC 1700	
Commissioner for Patents		
P.O. Box 1450		

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If there ar	e any additional charges, please charge Deposit Account No. 02-2666.		
	Respectfully submitted,		
	BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP		
Dated: 12/3	, 2003 Headley M. Molley Heather M. Molleyr Reg. No. 50,432		

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		First Named Inventor:	Steven N. Towle			
		Art Unit	1753			
				Examiner Name	McDonald, Rodney Glenn	
Sheet	1	of 1		Attorney Docket Number	42390P5783D	
			NON PATENT LIT	ERATURE DOCUMENTS		
Examiner Initials*	Cite No ¹	the item (bool	number(s), publi AL., Erosion of amor	TAL LETTERS), title of the artic serial, symposium, catalog, etc.), isher, city and/or country where p rphous hydrogenated boron-carbo 1-154, © 1996 Elsevier Science,	date, page(s), volume-issue published on thin films, Journal of	T ²
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	- 			ption spectroscopy of boron/carb	on films after keV deuterium -160, © 1994 Elsevier Science	

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